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Form PTO 1449 (Modified)	1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY DOCKET NO. 240779US2SRD DIV		SERIAL NO. 10/644,754		
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JIW	AO	9-91079	04/04/1997	JAPAN ·			X	
JW	AP	56-130608	10/13/1981	JAPAN			X	
JIW	AQ	6-164924	06/10/1994	JAPAN			X	
JW	AR	62-192714	08/24/1997	JAPAN			X	
WIL	AS	57-133411	08/18/1982	JAPAN			X	
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JIW	AA	4,641,349	02-1987	Flom et al.		_		
WIL	AB	6,057,909	05-2000	Yahav et al.				
JW	AC	6,256,067	07-2001	Yamada, Norihide		_		
JIW	AD	6,021,210	02-2000	Camus et al.	<u> </u>			
JIW	AE	5,801,763	09-1998	Suzuki, Hiroyoshi		_		
JW	AF	4,879,592	11-1989	Ernest, Paul W.				
JIW	AG	5,574,511	11-1996	Yang et al.				
JIW,	AH	4,967,276	10-1990	Murakami et al.				
MIC	Al	5,214,503	05-1993	Chiu et al.				
MIC	AJ	4,888,644	12-1989	Wilson, Thomas B.		_		
JIW	AK	6,144,366	11-2000	Numazaki et al.		-		
WIL	AL	6,292,169	09-2001	Numazaki et al.		_		
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		t considered. Include &	Apply of this form	with next communication to applicant.				

JUL 0 3 2006 SERIAL NO. ATTY DOCKET NO. OF DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE Form PTO 1 10/644,754 240779US2SRD DIV APPLICANT LIST OF REFERENCES CITED BY APPLICANT Shunichi NUMAZAKI, et al. GROUP FILING DATE 2173 2622 August 21, 2003 **U.S. PATENT DOCUMENTS** FILING DATE IF APPROPRIATE SUB **EXAMINER DOCUMENT** DATE NAME **CLASS** NUMBER CLASS INITIAL AΑ ΑB AC ΑD ΑE AF AG AΗ Αl ΑK AL AM ΑN **FOREIGN PATENT DOCUMENTS TRANSLATION** DOCUMENT DATE COUNTRY NUMBER NO Х MC AO 5-157525 06/22/1993 Japan ΑP AQ AR AS ΑT ΑU A۷ OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.) AW AX AY ΑZ Additional References sheet(s) attached **Date Considered** Examiner *Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.